

**IECEE**

**CB-SCHEME**

**OD-CB2000-Ed.12.0**

**OPERATIONAL & RULING DOCUMENTS**

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**OD-CB2000-Ed.12.0**

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**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components  
CB Scheme**

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Reference	Past Reference	Title	Issue
OD-CB1000-Ed.1.6		CB-Scheme Multilateral Agreement	Ed.1.6: 2010-05-07
<b>OD-CB2000-Ed.12.0</b>		<b>Index</b>	<b>Ed.12.0: 2010-07-09</b>
RD-CB2001-Ed.12.0		IECEE 01 Basic Rules	Ed.12.0: 2009-12-04
RD-CB2002-Ed.13.0		IECEE 02 Rules of procedure	Ed.13.0: 2009-12-04
OD-CB2003-Ed.9.3		List of Participants	Cancelled 2009-07-07
OD-CB2004-Ed.2.5	CBFORM4	Assessment Report for NCBs	Ed.2.5: 2010-02-05
OD-CB2004-Ed.2.5 Annexes		Example of use of Annexes	
OD-CB2005-Ed.2.3	CBFORM5	Assessment Report for CBTLs	Ed.2.3: 2010-02-05
OD-CB2005-Ed.2.2 Annexes		Example of use of Annexes	
OD-CB2006-Ed.3.4	CBFORM8	Guidelines and information for IECEE Assessors related to IECEE Peer Assessment	Ed.3.4: 2008-10-13
OD-CB2007-Ed.2.7		Documentation for applications	Ed.2.7: 2008-10-13
OD-CB2008-Ed.1.0		Initial Factory Audit/Inspection Form & Procedure	Ed.1.0: 2005-04-11
OD-CB2009-Ed.1.3	CBFORM7	Order Confirmation for Peer Assessor	Ed.1.3: 2005-02-10
OD-CB2010-Ed.1.3	CBFORM1	Application Form for NCBs	Ed.1.3:2006-06-23
OD-CB2011-Ed.1.3	CBFORM2	Application Form for CBTLs	Ed.1.3: 2007-09-04
OD-CB2012-Ed.1.4		Sub-Contracting of Testing Activities	Ed.1.4: 2008-10-13
<b>OD-CB2013-Ed.5.7</b>		<b>Listing of Authorized CB Test Certificates Signatories</b>	<b>Ed.5.6: 2010-07-09</b>
OD-CB2014-Ed.1.0		Annual Re-Assessment Report for CBTLs	Withdrawn 2008-03-03



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Reference	Past Reference	Title	Issue
OD-CB2015-Ed.1.3		Associated CB Testing Laboratories (ACTLs) to Operate with accepted CBTLs	Ed. 1.3: 2009-11-30
OD-CB2016-Ed.1.1		Check List for Product Certification Bodies	Ed.1.1: 2004-11-25
OD-CB2017-Ed.1.5		Check List for Testing and Calibration Laboratories	Ed.1.5: 2007-09-04
<b>OD-CB2018-Ed.8.1</b>		<b>List of Working Groups and Task Forces</b>	<b>Ed.8.0: 2010-07-09</b>
OD-CB2019		Manufacturers participating in IECEE Manufacturer's Testing Programs: SMT, TMP, WMT	Ongoing
OD-CB2019 LTR		Local technical representative (LTR) operating in Manufacturer's Testing Laboratory Programs	Ongoing
OD-CB2020-Ed.1.7		TRF Guide	Ed.1.7: 2010-01-25
OD-CB2021-Ed.1.1		Statement of Capability	Ed.1.1: 2006-06-23
OD-CB2022-Ed.1.6		IECEE-CMC Decisions of Current Interest	Cancelled: 2009-12-04
OD-CB2023-Ed.1.0		Rules for Observers invited to attend the IECEE Meetings, including Task Forces and Working Groups	Ed.1.0: 2001-10-19
OD-CB2024-Ed.1.0		Guideline for Testing Laboratories (CBTL) to prepare the List of Testing and Measuring Equipment	Ed.1.0: 2001-11-12
OD-CB2025-Ed.1.0		Assessment Report for MTLs	Ed.1.0: 2007-09-04
OD-CB2026-Ed.1.4		Finances	Ed.1.4: 2008-10-13
OD-CB2027-Ed.2.2		Use of Manufacturers' Test Laboratories: General Principles	Ed.2.1: 2007-09-04
OD-CB2028-Ed.1.2		Use of Manufacturers' Test Laboratories: Operation of TMP Procedure	Ed.1.2: 2007-09-04



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OD-CB2029-Ed.1.2		Use of Manufacturers' Test Laboratories: Operation of WMT Procedure	Ed.1.2: 2007-09-04
OD-CB2030-Ed.1.1		Use of Manufacturers' Test Laboratories: Operation of SMT Procedure	Ed.1.1: 2007-09-04
OD-CB2031-Ed.1.0		Use of Manufacturers' Test Laboratories: Operation of RMT Procedure	Ed.1.0: 2004-07-29
OD-CB2032-Ed.1.1		Assessment of Manufacturers Test Laboratories	Ed.1.1: 2007-10-05
OD-CB2033-Ed.2.0		Process elements related to infringements of the Rules	Ed.2.0: 2006-06-23
OD-CB2034-Ed.4.6		Use of a local technical representative (LTR) for IECEE TMP, WMT, SMT and RMT programmes	Ed.4.6: 2007-09-04
OD-CB2035-Ed.1.1		Update Questionnaire for IECEE Members	Ed.1.1: 2005-08-08
OD-CB2036-Ed.1.1		Acceptance of NCBs to take part in the Component Recognition Program	Ed.1.1: 2005-08-24
OD-CB2037-Ed.1.3		CB Test Certificates	Ed.1.3: 2009-12-04
OD-CB2038-Ed.1.0		Technical Review Process	Ed.1.0: 2007-08-20
OD-CB2039-Ed.1.0		Acceptance of Components within the IECEE CB Scheme and Component Acceptance Matrix	Ed.1.0: 2007-09-04
OD-CB2040-Ed.1.0		Common Understanding of ISO/IEC 17025	Ed 1.0: 2005-11-09
OD-CB2041-Ed.1.0		Guide on Product Families, Family Ranges or Series of Products	Ed.1.0: 2007-09-04
OD-CB2042-Ed.1.0		Fast Track Extension acceptance process for standards, editions, amendments for which the NCB has been already accepted for previous standard edition(s)	Ed.1.0: 2007-10-05

OD: Operational Document

RD: Ruling Document



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**COMPLIMENTARY DOCUMENT**

Archived Decisions of Current Interest – IECEE-CMC/270/INF
Customer Satisfaction Survey - IECEE-CMC/652/INF: published 2006-06-23

**COMMON OPERATIONAL DOCUMENTS APPROVED BY THE CMC**

<b>Reference</b>	<b>Title</b>	<b>Issue</b>
OD-CB2004C-Ed.2.1	Assessment Report for NCBs	Ed.2.1: 2007-11-09
OD-CB2005C-Ed.1.9	Assessment Report for CBTLs	Ed.1.9: 2007-11-09
OD-CB2014C-Ed.1.5	Declaration of Testing Experience	Cancelled: 2004-10-27
OD-CB2021C-Ed.1.2	Claim of Capability to test/certify	Ed.1.2: 2006-02-15